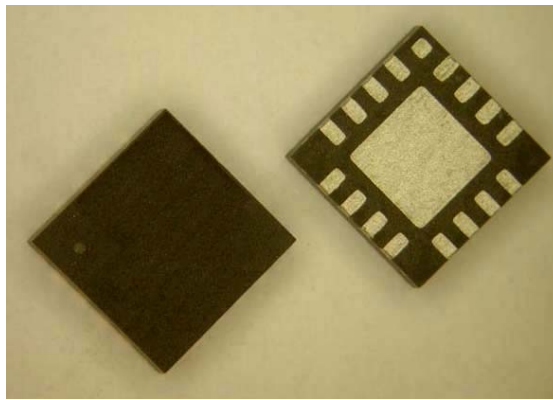




Product Description

The FPM2750QFN is a packaged pair of transistors (pHEMT) specifically optimized for balanced configuration systems. Our 0.25μm process ensures class-leading noise performance. The use of a small footprint plastic package allows for a cost effective total system implementation.



Optimum Technology Matching® Applied

- ☐ GaAs HBT
- ☐ GaAs MESFET
- ☐ InGaP HBT
- ☐ SiGe BiCMOS
- ☐ Si BiCMOS
- ☐ SiGe HBT
- ☒ GaAs pHEMT
- ☐ Si CMOS
- ☐ Si BJT
- ☐ GaN HEMT
- ☐ InP HBT
- ☐ RF MEMS
- ☐ LDMOS

Features

- Balanced Low Noise Amplifier Module
- Excellent Noise figure: 0.4 dB at 1850 MHz
- Low Drive Current: 40 mA (3.0 V)
- Combined IP3: 36 dBm (100 mA)
- Combined P1dB: 23 dBm (100 mA)

Applications

- Wireless Infrastructure: Tower-Mounted Amplifiers and Front End LNAs for EGSM/PCS/WCDMA/UMTS Base Stations
- High Intercept-Point LNAs

RF/DC Parameter	Electrical Specification			Unit	Condition
	Min.	Typ.	Max.		
Noise Figure (NF)		0.4		dB	$V_{DS}=3V, I_{DS}=40mA$
		0.6		dB	$V_{DS}=4V, I_{DS}=100mA$
OIP ₃ (15 dB to 5 dB below P _{1dB})		32		dBm	$V_{DS}=3V, I_{DS}=40mA$
	33	36		dBm	$V_{DS}=4V, I_{DS}=100mA$
Small-Signal Gain in Balanced Mode		18.5		dB	$V_{DS}=3V, I_{DS}=40mA$
	17.5	20		dB	$V_{DS}=4V, I_{DS}=100mA$
P _{1dB} in Balanced Mode		21		dBm	$V_{DS}=3V, I_{DS}=40mA$
	21.5	23.5		dBm	$V_{DS}=4V, I_{DS}=100mA$
Small-Signal Gain (SSG)		19.0		dB	$V_{DS}=3V, I_{DS}=40mA$
		19.5		dB	$V_{DS}=4V, I_{DS}=100mA$
OP _{1dB} at Gain Compression		17.5		dBm	$V_{DS}=3V, I_{DS}=40mA$
		17.5		dBm	$V_{DS}=4V, I_{DS}=100mA$
Saturated Drain-Source Current (I _{DSS})	185	230	280	mA	$V_{DS}=1.3V, V_{GS}=0V$
Maximum Drain-Source Current (I _{MAX})		375		mA	$V_{DS}=1.3V, V_{GS}=+1V$
Transconductance (GM)		200		ms	$V_{DS}=1.3V, V_{GS}=0V$
Gate-Source Leakage Current (I _{GS0})				μA	$V_{GS}=-5V$
Pinch-Off Voltage (V _P)	0.7	1.0	1.3	V	$V_{DS}=1.3V, I_{DS}=0.75mA$
Gate-Source Breakdown V _{itg} (V _{BDS})		16		V	$I_{GS}=0.75mA$
Gate-Drain Breakdown V _{itg} (V _{BGD})		18		V	$I_{DS}=0.75mA$
Thermal Resistivity (θ _{JC}) *		124		°C/W	1W dissipation, case temperature 22°C

*Note: RF specification measured at f=1850MHz using CW signal (except as noted). T_{AMBIENT}=22°C.

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Absolute Maximum Ratings (per Transistor)¹

Parameter	Rating	Unit
Drain-Source Voltage (V_{DS})	6	V
Gate-Source Voltage (V_{GS})	-3	V
Drain-Source Current (I_{DS}) ($V_{DS} < 2V$)	I_{DSS}	
Gate Current (I_G) (Forward or reverse)	7.5	mA
RF Input Power (P_{IN}) ² (Under any acceptable bias state)	150	mW
Channel Operating Temperature (T_{CH}) (Under any acceptable bias state)	175	°C
Storage Temperature (T_{STG}) (Non-Operating Storage)	-55 to 150	°C
Total Power Dissipation (P_{TOT}) ³	1	W
Gain Compression (Under bias conditions)	5	dB

Notes: ¹ $T_{AMBIENT} = 22^\circ\text{C}$ unless otherwise noted; exceeding any one of these absolute maximum ratings may cause permanent damage to the device.

²Max. RF input limit must be further limited if input VSWR > 2.5:1.

³Total Power Dissipation (P_{TOT}) defined as $(P_{DC} + P_{IN}) - P_{OUT}$, where P_{DC} : DC Bias Power, P_{IN} : RF Input Power, P_{OUT} : RF Output Power.

Total Power Dissipation to be de-rated as follows above 22°C :

$P_{TOT} = (150 - T_{CASE}) / \theta_{JC}$, where T_{CASE} = temperature of the thermal pad on the underside of the package.

θ_{JC} increases linearly from 124°C/W at a T_{CASE} of 22°C to 145°C/W at a T_{CASE} of 145°C . (Coefficient of de-rating formula is Thermal Conductivity.)

Information on the mounting of QFN-style packages for optimum thermal performance is available on request.



Caution! ESD sensitive device.

Exceeding any one or a combination of the Absolute Maximum Rating conditions may cause permanent damage to the device. Extended application of Absolute Maximum Rating conditions to the device may reduce device reliability. Specified typical performance or functional operation of the device under Absolute Maximum Rating conditions is not implied.

RoHS status based on EUDirective 2002/95/EC (at time of this document revision).

The information in this publication is believed to be accurate and reliable. However, no responsibility is assumed by RF Micro Devices, Inc. ("RFMD") for its use, nor for any infringement of patents, or other rights of third parties, resulting from its use. No license is granted by implication or otherwise under any patent or patent rights of RFMD. RFMD reserves the right to change component circuitry, recommended application circuitry and specifications at any time without prior notice.

Biasing Guidelines

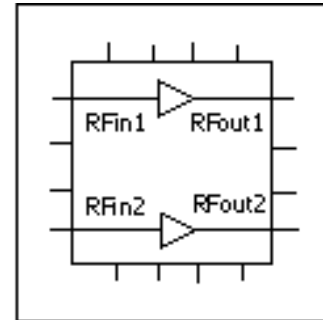
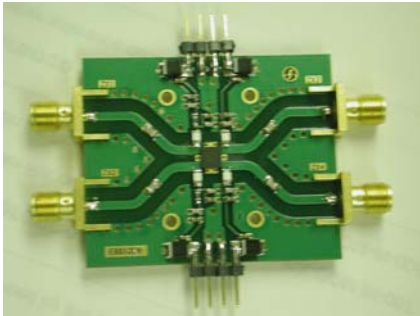
Active bias circuits provide good performance stabilization over variations of operating temperature, but require a larger number of components compared to self-biased or dual-biased circuits. Such circuits should include provisions to ensure that gate bias is applied before drain bias, otherwise the pHEMT may be induced to self-oscillate. Contact your Sales Representative for additional information.

Dual-bias circuits are relatively simple to implement, but will require a regulated negative voltage supply for depletion-mode devices used in the FPM2750QFN.

For standard Class A operation, a 50% I_{DSS} bias point is recommended. A small amount of RF gain expansion prior to the onset of compression is normal for this operating point. Class A/B bias of 25% to 33% offers an optimized solution for NF and OIP₃.

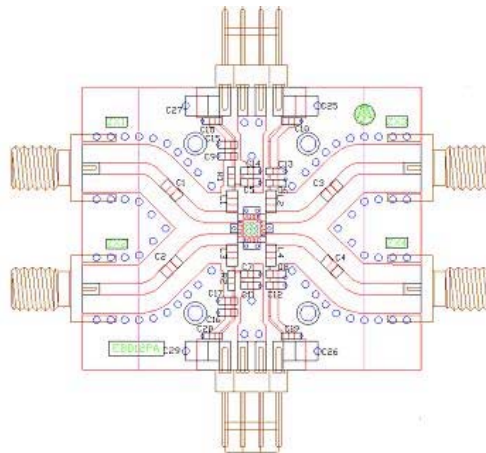
Reference Design (1850 MHz Single-Ended Operation)

Evaluation board drawing in AutoCAD™ format available on request.



Package Schematic

Board Layout

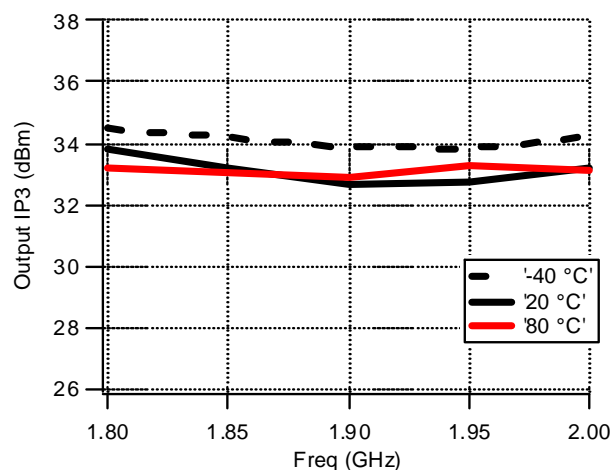
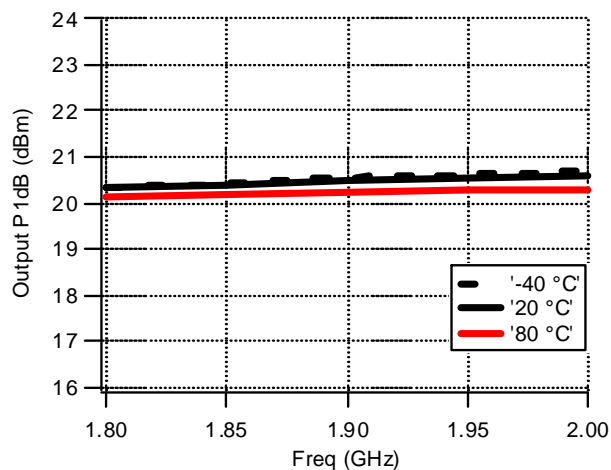
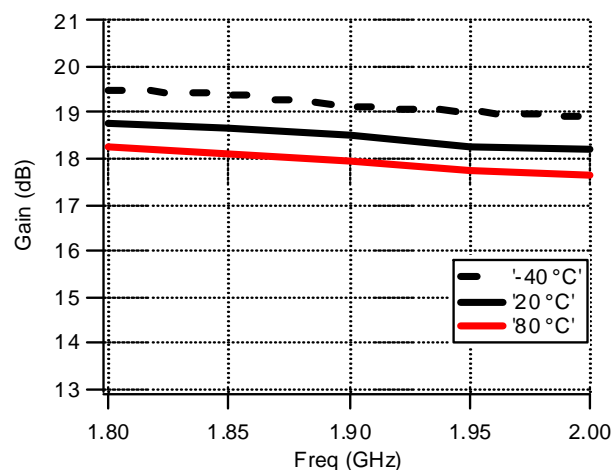
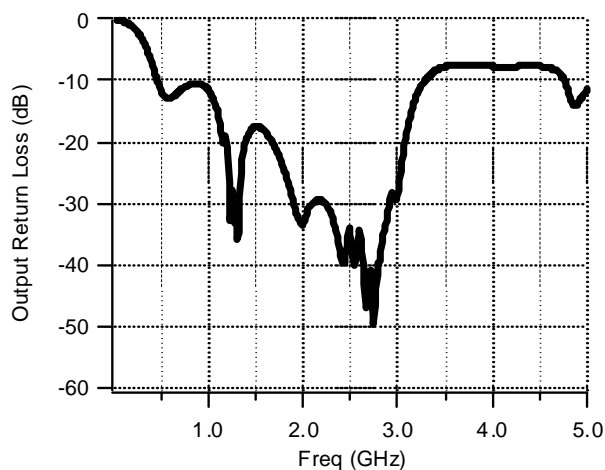
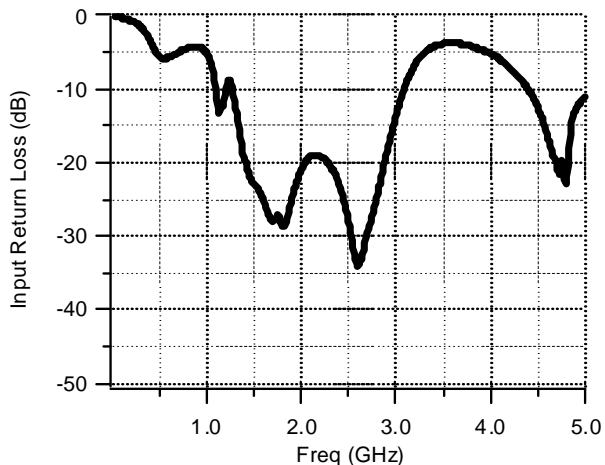
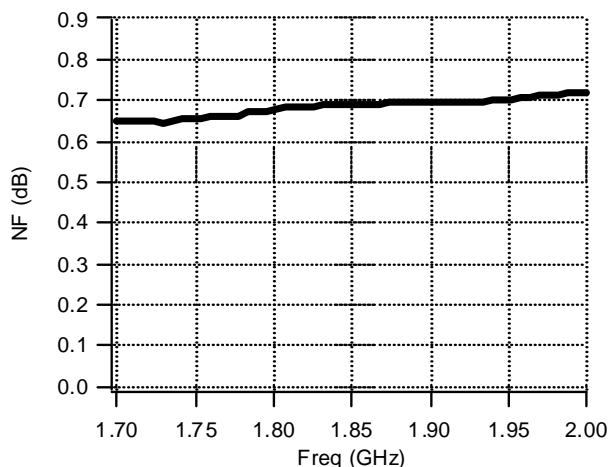


Bill of Materials

Designator	Supplier	Part Number	Description	Quantity
C1, C2, C3, C4	RS Components	464-6587	CAP-20pF-0805-±5%-50V(min)-LOW_ESR	4
C5, C6, C7, C8, C9, C17	RS Components	464-6385	CAP-10pF-0603-5%-50V-COG	6
C10, C18, C19, C20	RS Components	264-4602	CAP-22nF-0603-10%-50V	4
C11, C12, C13, C14, C15, C16	RS Components	464-6543	CAP-47nF-0603-+80/-20%-50V-Y5V	6
C25, C26, C27, C29	RS Components	406-0006	CAP-1uF-CASEB-20%-35V-TANT	4
L1, L2, L3, L4	RS Components	484-1372	IND-12nH-2012(0805)-5%-600mA-HQ	4
Q2	RFMD	FPM2750QFN	Dual FPD750-QFN 4x4	1
R1, R2	RS Components	213-2042	Resist-22Ω-1608(0603)-1%-0.1W	2
R3, R4, R5, R6	RS Components	363-4707	SMA Side-Mount RF Connector	4
(V1, V2)	RS Components	453-173	DC Connector (4-way)	2
Evaluation board	RFMD	EBD15PA	31mil thick FR4, 1/2 Ounce Cu on both sides	1

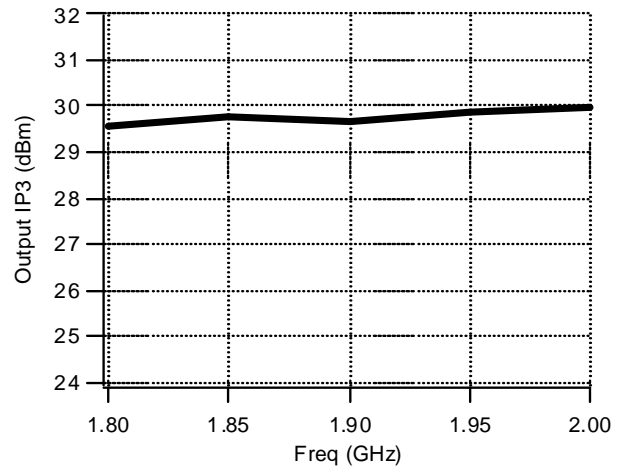
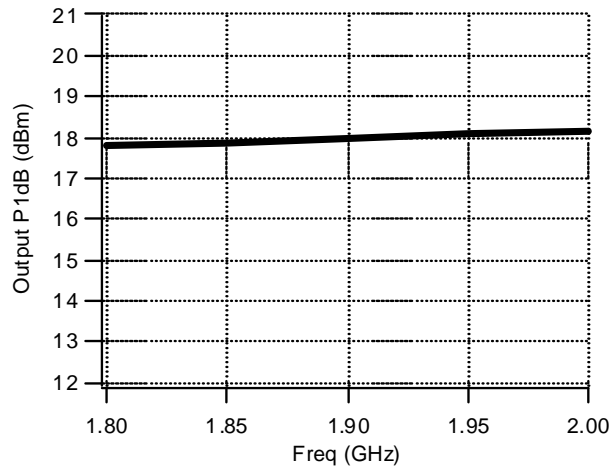
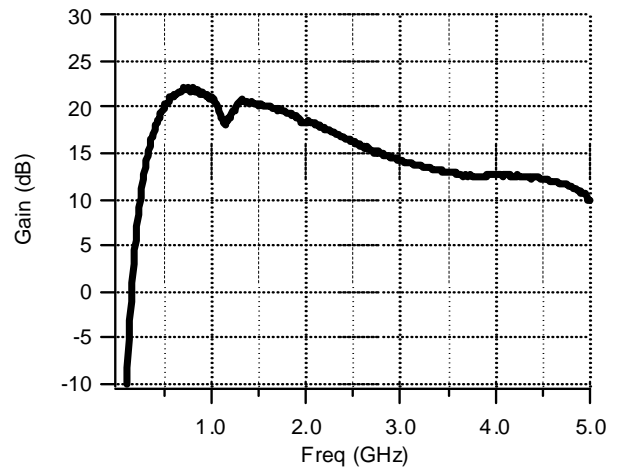
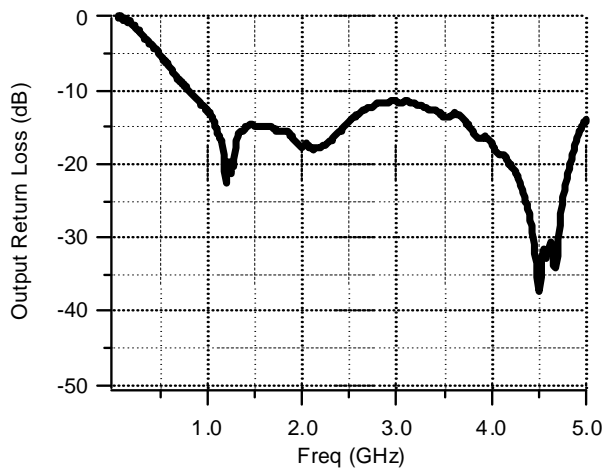
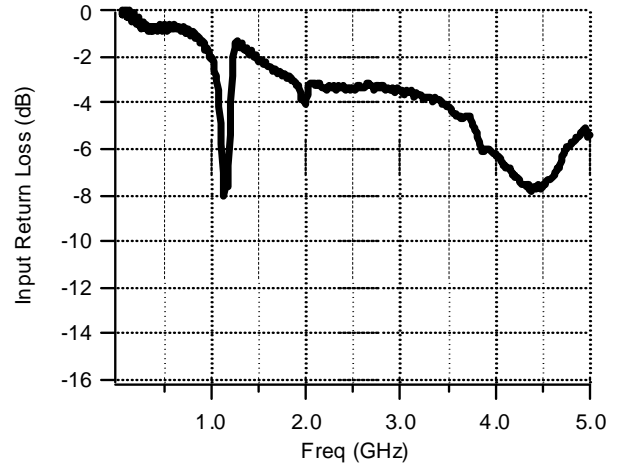
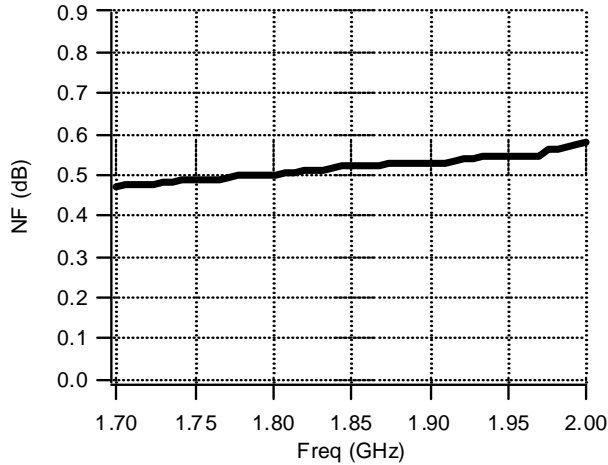
Typical Measured Evaluation Board Performance (Balanced Operation)

$V_{DS}=3V$, $I_{DS}=40mA$ (per device), 50Ω environment and $T_A=+22^\circ C$ unless stated otherwise. All measurements shown are referenced to evaluation board connectors.

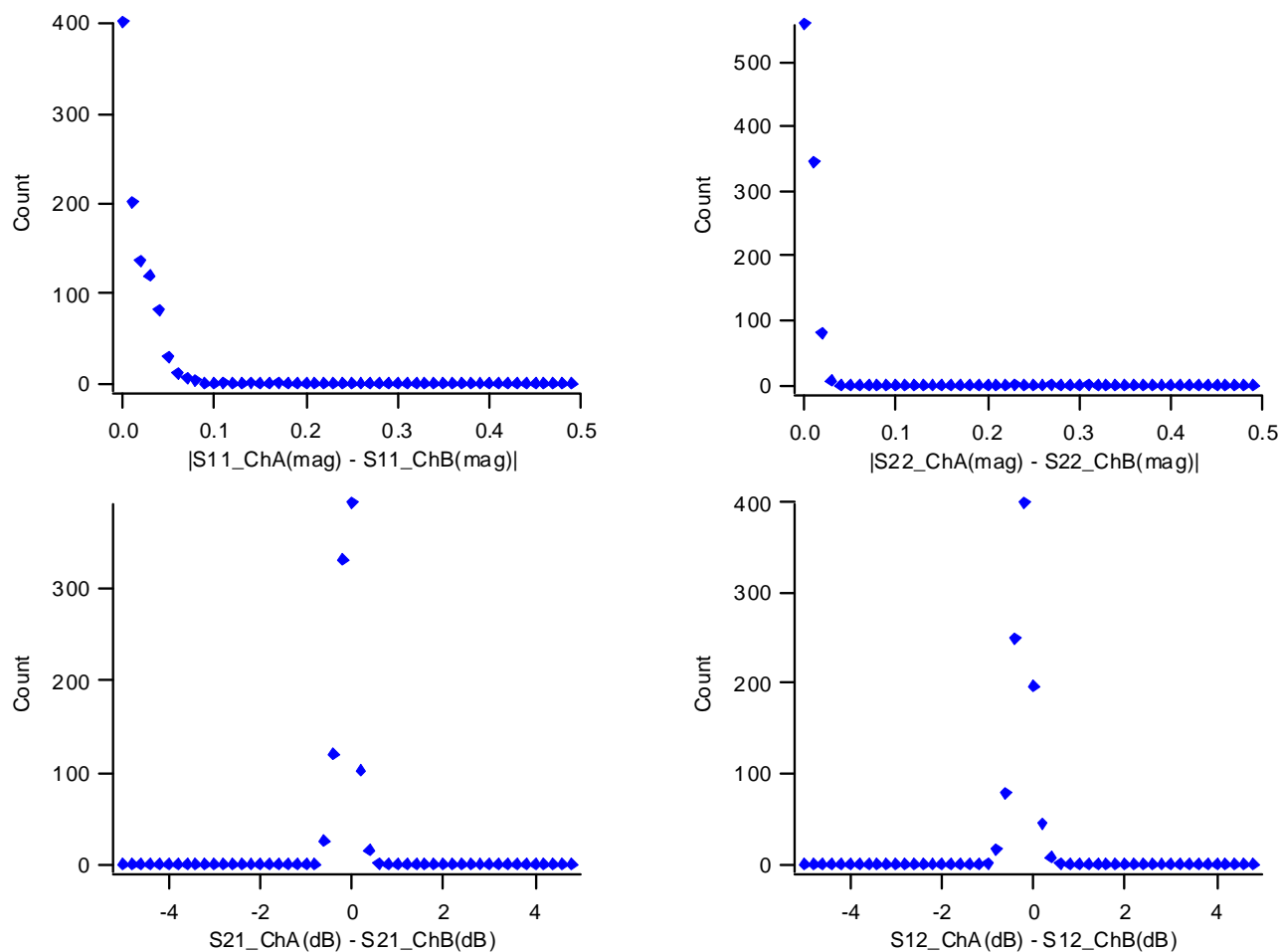


Typical Measured Evaluation Board Performance (Single-Ended Operation)

$V_{DS}=3V$, $I_{DS}=40mA$ (per device), 50Ω environment and $T_A=+22^\circ C$ unless stated otherwise. All measurements shown are referenced to evaluation board connectors.



Typical Small Signal Magnitude Difference Within a Single Package



The histograms above represent the distribution of the asymmetry of RF parameters for the devices within a package. ChA and ChB are the two devices within the same package. The sample size for the histograms above is 1000 parts.

Parameter	Median	Standard Deviation	Test Limit	CPK
$ S11_ChA(mag) - S11_ChB(mag) $	0.0001	0.027	0.1	1.3
$ S22_ChA(mag) - S22_ChB(mag) $	0.0001	0.019	0.1	1.7
$S21_ChA(dB) - S21_ChB(dB)$	0.006	0.408	± 0.75	0.68
$S12_ChA(dB) - S12_ChB(dB)$	-0.128	0.205	± 0.75	1.43

Part Identification

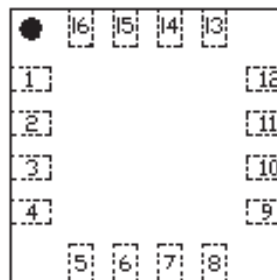
Marking



1st row Device code 'P8F'

2nd row Trace Code to be assigned by SubCon

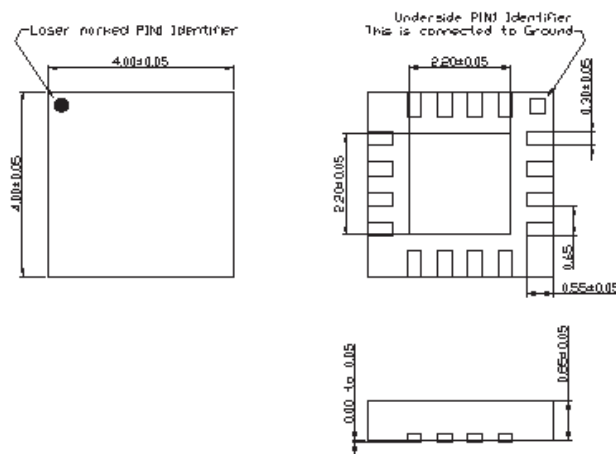
Pad Layout



Terminal	Function
1-4, 6, 15	Source 1
5	RFin 1/Gate 1
7, 9-12, 14	Source 2
8	RFin 2/Gate 2
13	RFout 2/Drain 2
16	RFout 1/Drain 1

Note: Dimensions in millimeters. Center paddle and pin 1 identifier are grounded.

Package Drawing



Tape and Reel

Tape and reel information on this material is in accordance with EIA-481-1 except where exceptions are identified.

Preferred Assembly Instructions

This package is compatible with both lead-free and leaded solder reflow processes as defined within IPC/J-STD-020C. The maximum package temperature should not exceed 260°C.



Handling Precautions

To avoid damage to the devices, care should be exercised during handling. Proper Electrostatic Discharge (ESD) precautions should be observed at all stages of storage, handling, assembly, and testing.

ESD Rating

These devices should be treated as Class 0 (0V to 250V) using the human body model as defined in JEDEC Standard No. 22-A114. Further information on ESD control measures can be found in MIL-STD-1686 and MIL-HDBK-263..

MSL Rating

The device has an MSL rating of Level 1. To determine this rating, preconditioning was performed to the device per the Pb-free solder profile defined within IPC/JEDEC, J-STD-020C, moisture/reflow sensitivity classification for non-hermetic solid state.

Application Notes and Design Data

Application Notes and design data including S-parameters are available from <http://www.rfmd.com>.

Reliability

An MTTF of 4.2 million hours at a channel temperature of 150°C is achieved for the process used to manufacture this device.

Disclaimers

This product is not designed for use in any space-based or life-sustaining/supporting equipment.

Ordering Information

Description	Ordering Code
Packaged pHEMT	FPM2750QFN
Evaluation Board (1.85 GHz)	FPM2750QFNPCK

Delivery Quantity	Ordering Code
Reel of 1000	FPM2750QFN
Reel of 100	FPM2750QFN5R
Bag of 25	FPM2750QFN5Q
Bag of 5	FPM2750QFN5B